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2. The testability features of the 3rd generation ColdFire^(R) family of microprocesso

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3. On-the-shelf core pattern methodology for ColdFire(R) microprocessor cores

McLaurin, T.L.; Potter, J.C.; Test Conference, 2000. Proceedings. International 3-5 Oct. 2000 Page(s):1100 - 1107

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4. The testability features of the MCF5407 containing the 4th generation ColdFire(R) microprocessor core

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5. The testability features of the ARM1026EJ microprocessor core

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☐**1. ETM10 incorporates hardware segment of IEEE P1500**McLaurin, T.; Ghosh, S.;
Design & Test of Computers, IEEE
Volume 19, Issue 3, May-June 2002 Page(s):6 - 11[AbstractPlus](#) | [References](#) | Full Text: [PDF](#)(245 KB) IEEE JNL☐**2. Test development for a third-version ColdFire microprocessor**Crouch, A.L.; Mateja, M.; McLaurin, T.L.; Potter, J.C.; Tran, D.;
Design & Test of Computers, IEEE
Volume 17, Issue 4, Oct.-Dec. 2000 Page(s):29 - 37[AbstractPlus](#) | [References](#) | Full Text: [PDF](#)(152 KB) IEEE JNL☐**3. The testability features of the 3rd generation ColdFire^(R) family of microprocesso**Crouch, A.L.; Mateja, M.; McLaurin, T.L.; Potter, J.C.; Tran, D.;
Test Conference, 1999. Proceedings. International
28-30 Sept. 1999 Page(s):913 - 922[AbstractPlus](#) | Full Text: [PDF](#)(800 KB) IEEE CNF☐**4. Preliminary Outline of the IEEE PI 500 Scalable Architecture for Testing Embedd**Adham, S.; Burek, D.; Clark, C.J.; Collins, M.; Giles, G.; Sales, A.; Marinissen, E.J.; Mc
Monzel, J.; Muradali, F.; Rajoki, J.; Rajsuman, R.; Ricchatti, M.; Stannard, D.; Udell, J.;
Whetsel, L.; Zamfirescu, A.; Zorian, Y.;
VLSI Test Symposium, 1999. Proceedings. 17th IEEE
25-29 April 1999 Page(s):483 - 488[AbstractPlus](#) | Full Text: [PDF](#)(436 KB) IEEE CNF☐**5. On-the-shelf core pattern methodology for ColdFire(R) microprocessor cores**McLaurin, T.L.; Potter, J.C.;
Test Conference, 2000. Procéedings. International
3-5 Oct. 2000 Page(s):1100 - 1107[AbstractPlus](#) | Full Text: [PDF](#)(668 KB) IEEE CNF☐**6. The testability features of the MCF5407 containing the 4th generation ColdFire(R) microprocessor core**McLaurin, T.L.; Frederick, F.;
Test Conference, 2000. Proceedings. International
3-5 Oct. 2000 Page(s):151 - 159

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- ☐ 7. **The testability features of the ARM1026EJ microprocessor core**
McLaurin, T.L.; Frederick, F.; Slobodnik, R.;
Test Conference, 2003. Proceedings. ITC 2003. International
Volume 1, Sept. 30-Oct. 2, 2003 Page(s):773 - 782

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Original Classifications

11 714/726
5 714/718
3 714/727
2 365/201
2 708/130
2 714/733

PLUS

Cross-Reference Classifications

5 714/733
5 714/734
4 324/73.1
4 714/724
4 714/726
3 365/201
3 714/727
2 324/763
2 712/37
2 714/731

Combined Classifications

15 714/726
7 714/733
6 714/718
6 714/727
5 365/201
5 714/724
5 714/734
4 324/73.1
3 712/37
2 324/763
2 365/233
2 365/49
2 708/130
2 714/731
2 714/736

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- 15 714/726 (11 OR, 4 XR)
Class 714 : ERROR DETECTION/CORRECTION AND FAULT
DETECTION/RECOVERY
714/699 PULSE OR DATA ERROR HANDLING
714/724 .Digital logic testing
714/726 ..Scan path testing (e.g., level sensitive scan
design (LSSD))
- 7 714/733 (2 OR, 5 XR)
Class 714 : ERROR DETECTION/CORRECTION AND FAULT
DETECTION/RECOVERY
714/699 PULSE OR DATA ERROR HANDLING
714/724 .Digital logic testing
714/733 ..Built-in testing circuit (BILBO)
- 6 714/718 (5 OR, 1 XR)
Class 714 : ERROR DETECTION/CORRECTION AND FAULT
DETECTION/RECOVERY
714/699 PULSE OR DATA ERROR HANDLING
714/718 .Memory testing
- 6 714/727 (3 OR, 3 XR)
Class 714 : ERROR DETECTION/CORRECTION AND FAULT
DETECTION/RECOVERY
714/699 PULSE OR DATA ERROR HANDLING
714/724 .Digital logic testing
714/726 ..Scan path testing (e.g., level sensitive scan
design (LSSD))
714/727 ...Boundary scan
- 5 365/201 (2 OR, 3 XR)
Class 365 : STATIC INFORMATION STORAGE AND RETRIEVAL
365/189.01 READ/WRITE CIRCUIT
365/201 .Testing
- 5 714/724 (1 OR, 4 XR)
Class 714 : ERROR DETECTION/CORRECTION AND FAULT
DETECTION/RECOVERY
714/699 PULSE OR DATA ERROR HANDLING
714/724 .Digital logic testing
- 5 714/734 (0 OR, 5 XR)
Class 714 : ERROR DETECTION/CORRECTION AND FAULT
DETECTION/RECOVERY
714/699 PULSE OR DATA ERROR HANDLING
714/724 .Digital logic testing
714/734 ..Structural (in-circuit test)
- 4 324/73.1 (0 OR, 4 XR)
Class 324 : ELECTRICITY: MEASURING AND TESTING
324/73.1 PLURAL, AUTOMATICALLY SEQUENTIAL TESTS
- 3 712/37 (1 OR, 2 XR)
Class 712 : ELECTRICAL COMPUTERS AND DIGITAL PROCESSING
SYSTEMS: PROCESSING ARCHITECTURES AND INSTRUCTION
PROCESSING
712/1 PROCESSING ARCHITECTURE
712/32 .Microprocessor or multichip or multimodule
processor having sequential program control

- 712/37 ..Programmable (e.g., EPROM)
- 2 324/763 (0 OR, 2 XR)
 Class 324 : ELECTRICITY: MEASURING AND TESTING
 324/500 FAULT DETECTING IN ELECTRIC CIRCUITS AND OF
 ELECTRIC COMPONENTS
 324/537 ..of individual circuit component or element
 324/763 ..DUT including test circuit
- 2 365/233 (1 OR, 1 XR)
 Class 365 : STATIC INFORMATION STORAGE AND RETRIEVAL
 365/230.01 ADDRESSING
 365/233 ..Sync/clocking
- 2 365/49 (1 OR, 1 XR)
 Class 365 : STATIC INFORMATION STORAGE AND RETRIEVAL
 365/49 ASSOCIATIVE MEMORIES
- 2 708/130 (2 OR, 0 XR)
 Class 708 : ELECTRICAL COMPUTERS: ARITHMETIC PROCESSING
 AND CALCULATING
 708/100 ELECTRICAL DIGITAL CALCULATING COMPUTER
 708/130 ..Programmable calculator
- 2 714/731 (0 OR, 2 XR)
 Class 714 : ERROR DETECTION/CORRECTION AND FAULT
 DETECTION/RECOVERY
 714/699 PULSE OR DATA ERROR HANDLING
 714/724 ..Digital logic testing
 714/726 ..Scan path testing (e.g., level sensitive scan
 design (LSSD))
 714/731 ...Clock or synchronization
- 2 714/736 (1 OR, 1 XR)
 Class 714 : ERROR DETECTION/CORRECTION AND FAULT
 DETECTION/RECOVERY
 714/699 PULSE OR DATA ERROR HANDLING
 714/724 ..Digital logic testing
 714/736 ..Device response compared to expected
 fault-free response

PLUS Search Results for S/N 10812309, Searched June 17, 2005

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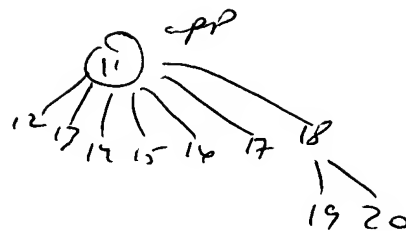
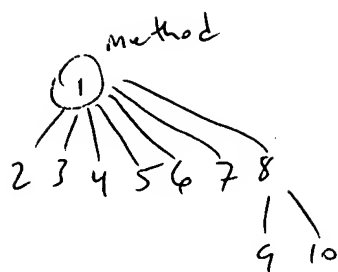
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Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
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L2	4183	324/537,763,765.ccls.	US-PGPUB; USPAT	OR	ON	2005/06/17 12:14
L3	4308	714/724,726,727,729,733,734, 718.ccls.	US-PGPUB; USPAT	OR	ON	2005/06/17 12:15
L4	8620	1 or 2 or 3	US-PGPUB; USPAT	OR	ON	2005/06/17 12:15

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702 / 117, 118, 120, 122

724 / 537, 763, 765

714 / 724, 726, 727, 729, 733, 734, 718
